

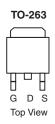
IPB50N10S3L-16-VB Datasheet N-Channel 100-V (D-S) MOSFET

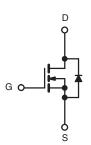
PRODUCT SUMMARY				
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)		
100	0.010 at V _{GS} = 10 V	100		
	0.023 at V _{GS} = 4.5 V	85		

FEATURES

- Trench Power MOSFET
- 175 °C Maximum Junction Temperature
- Compliant to RoHS Directive 2002/95/EC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted					
Parameter			Limit	Unit	
Drain-Source Voltage			100	V	
Gate-Source Voltage			± 20	V	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	I _D	100	A	
	T _C = 125 °C	טי	75 ^a		
Pulsed Drain Current	I_{DM}	300	A		
Avalanche Current	L = 0.1 mH	I _{AS}	75		
Single Pulse Avalanche Energy ^b	L = 0.1 IIII1	E _{AS}	280	mJ	
Mariana Darray Dissipation	T _C = 25 °C (TO-220AB and TO-263)	P_{D}	250 ^c	W	
Maximum Power Dissipation ^b	T _A = 25 °C (TO-263) ^d	' D	3.75		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Limit	Unit	
Junction-to-Ambient	PCB Mount (TO-263) ^d	- R _{thJA}	40	°C/W	
Junction-to-Ambient	Free Air (TO-220AB)	' 'thJA	62.5		
Junction-to-Case		R _{thJC}	0.6		

Notes:

- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			W
Gate-Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2		4	V
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		V _{DS} = 100 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 125 °C			50	μΑ
		V _{DS} = 100 V, V _{GS} = 0 V, T _J = 175 °C			250	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} = \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
		V _{GS} = 10 V, I _D = 30 A		0.010		1
		V _{GS} = 4.5 V, I _D = 20 A		0.023		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 30 A, T _J = 125 °C		0.020		Ω
		V _{GS} = 10 V, I _D = 30 A, T _J = 175 °C		0.030		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 30 A	25			S
Dynamic ^b						
Input Capacitance	C _{iss}			6550		
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		665		pF
Reverse Transfer Capacitance	C _{rss}	1		265		
Total Gate Charge ^c	Qg			105	160	
Gate-Source Charge ^c	Q_{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 85 \text{ A}$		17		nC
Gate-Drain Charge ^c	Q_{gd}	1		23		
Turn-On Delay Time ^c	t _{d(on)}			12	25	
Rise Time ^c	t _r	$V_{DD} = 50 \text{ V}, R_{L} = 0.6 \Omega$		90	135	
Turn-Off DelayTime ^c	t _{d(off)}	$I_D\cong 85$ A, $V_{GEN}=10$ V, $R_g=2.5~\Omega$		55	85	ns
Fall Time ^c	t _f	1		130	195	
Source-Drain Diode Ratings and Char	racteristics T _C	= 25 °C ^b				
Continuous Current	I _S				85	
Pulsed Current	I _{SM}				240	Α
Forward Voltage ^a	V _{SD}	I _F = 85 A, V _{GS} = 0 V		1.0	1.5	V
Reverse Recovery Time	t _{rr}			85	140	ns
Peak Reverse Recovery Current	I _{RM(REC)}	I _F = 50 A, dI/dt = 100 A/μs		4.5	7	Α
Reverse Recovery Charge	Q _{rr}	1		0.17	0.35	μС

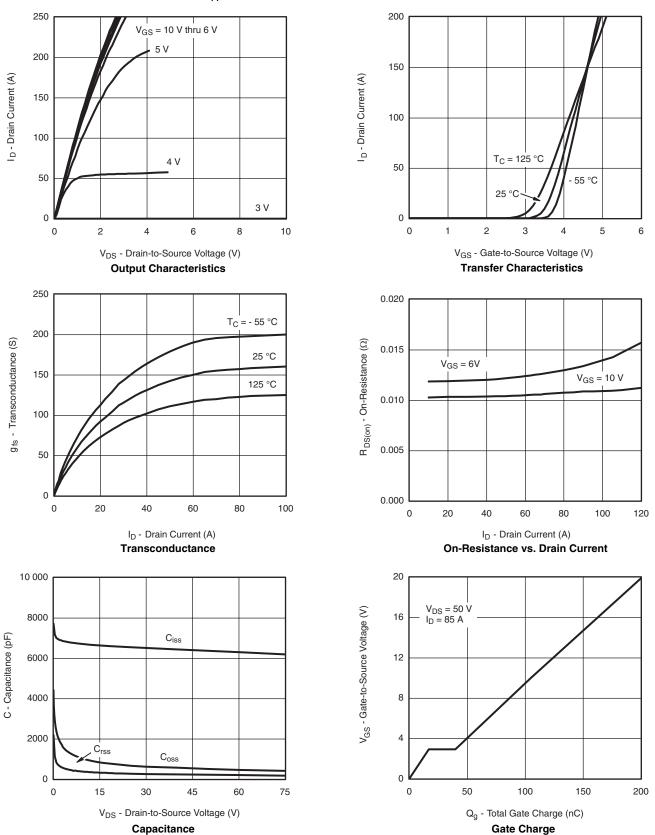
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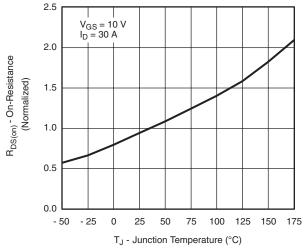


TYPICAL CHARACTERISTICS $T_A = 25 \, ^{\circ}C$, unless otherwise noted

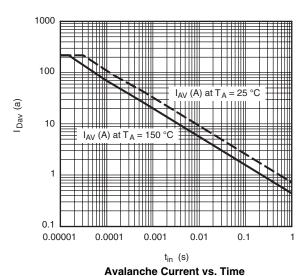




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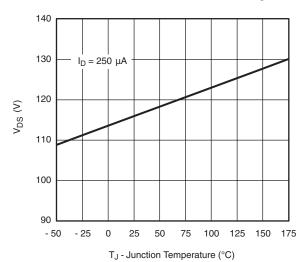


On-Resistance vs. Junction Temperature



T_J = 150 °C T_J = 25 °C T_J

Source-Drain Diode Forward Voltage

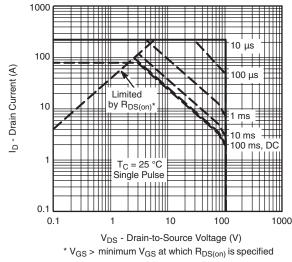


T_J - Drain-Source Breakdown vs. Junction-Temperature

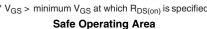


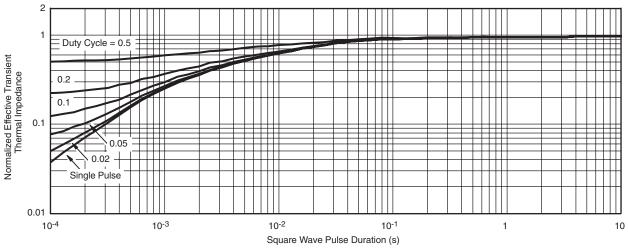
THERMAL RATINGS





Maximum Avalanche and Drain Current vs. Case Temperature





Normalized Thermal Transient Impedance, Junction-to-Case



MILLIMETERS

MAX.

4.826

0.990

0.889

1.397

0.457

0.711

0.431

0.685

1.397

9.652

6.096

1.067

1.397

1.321

10.414

_

9.525

1.981

1.397

15.875

2.794

1.397

1.778

0.050

2.54 BSC

0.254 BSC

MIN.

4.064

0.508

0.508

1.143

0.330

0.584

0.330

0.584

1.143

8.636

5.588

0.965

1.143

1.118

9.652

6.223

9.017

1.829

1.143

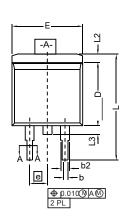
14.605

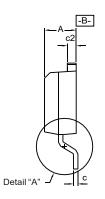
2.286

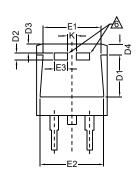
1.016

1.270

TO-263 (D²PAK): 3-LEAD







INCHES

MAX.

0.190

0.039

0.035

0.055

0.018

0.028

0.017

0.027

0.055

0.380

0.240

0.042

0.055

0.052

0.410

0.375

0.078

0.055

0.625

0.110

0.055

0.070

MIN.

0.160

0.020

0.020

0.045

0.013

0.023

0.013

0.023

0.045

0.340

0.220

0.038

0.045

0.044

0.380

0.245

0.355

0.072

0.045

0.575

0.090

0.040

0.050

0.100 BSC

DIM.

b

b1

b2

c2

D

D1

D2

D3 D4

Е

E1

E2

E3

е Κ

L

L1

L2

L3

с1

Thin lead

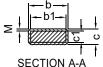
Thick lead

Thin lead

Thick lead



DETAIL A (ROTATED 90°)



_	ļ		b →		+
_	T			5	ပ
	SE	СТ	ION	î <u>A-A</u>	t

- 1. Plane B includes maximum features of heat sink tab and plastic.
- 2. No more than 25 % of L1 can fall above seating plane by max.
- 3. Pin-to-pin coplanarity max. 4 mils.
- 4. *: Thin lead is for SUB, SYB. Thick lead is for SUM, SYM, SQM.
- 5. Use inches as the primary measurement. 6 This feature is for thick lead.

L4	0.010 BSC				
М	-	0.002			
ECN: T13-0707-Rev. K, 30-Sep-13					
DWG: 5843					



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